

Test	Conditions	Sample Size	Generic	Package	Results
ESD- FICDM	ANSI/ESD STM5.3.1-1999	1x15	ADG526A	PDIP	In Process
		1x15	ADG526A	PLCC	In Process
		1x15	ADG526A	SOIC_W	In Process
		1x15	ADG527A	PDIP	In Process
		1x15	ADG527A	PLCC	In Process
		1x15	ADG527A	SOIC_W	In Process
ESD-HBM	ANSI/ESD STM5.1-2007	1x24	ADG526A	SOIC_W	In Process
		1x24	ADG527A	SOIC_W	In Process
ESD-MM	ANSI/ESD STM5.2-1999	1x6	ADG526A	SOIC_W	In Process
		1x6	ADG527A	SOIC_W	In Process
Latch-up	JESD78	1x6	ADG526A	SOIC_W	In Process
		1x6	ADG527A	SOIC_W	In Process

PDIP

Test	Conditions	Sample Size	Results
Autoclave	JEDEC-STD-22-Method A102	2x77	Pass
		1x77	Pass
		1x77	Pass
		1x77	Pass
		2x50	Pass
		1x50	Pass
Highly Accelerated Stress Test (HAST)	JEDEC-STD-22-Method A110	3x77	Pass
		2x50	Pass
High Temperature Storage (HTS)	JEDEC-STD-22-Method A103	2x77	Pass
		1x77	Pass
Temperature Cycle	JEDEC-STD-22-Method A104	3x77	Pass
		3x77	Pass
		2x50	Pass
		1x50	Pass
		1x50	Pass

PLCC

Test	Conditions	Sample Size	Results
Autoclave*	JEDEC-STD-22-Method A102	3x77	Pass
		4x77	Pass
		3x60	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC-STD-22-Method A110	3x77	Pass
High Temperature Storage (HTS)	JEDEC-STD-22-Method A103	1x77	Pass
		1x77	Pass
Temperature Cycle*	JEDEC-STD-22-Method A104	3x77	Pass
		3x77	Pass

*Preconditioned Per JEDEC/IPC J-STD-020

SOIC W

Test	Conditions	Sample Size	Results
Autoclave*	JEDEC-STD-22-Method A102	1x45	Pass
		1x50	Pass
		2x82	Pass
		1x50	Pass
		3x82	Pass
		3x82	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC-STD-22-Method A110	3x82	Pass
		3x82	Pass
		3x82	Pass
		1x45	Pass
		1x25	Pass
High Temperature Storage (HTS)*	JEDEC-STD-22-Method A103	1x50	Pass
High Temperature Storage (HTS)	JEDEC-STD-22-Method A103	1x82	Pass
		1x82	Pass
		1x82	Pass
		1x50	Pass
		1x49	Pass
Temperature Cycle*	JEDEC-STD-22-Method A104	2x82	Pass
		1x50	Pass
		1x50	Pass
		3x82	Pass
		3x82	Pass

*Preconditioned Per JEDEC/IPC J-STD-020

BiCMOS at ADI Limerick

Test	Conditions	Sample Size	Results
Early Life Failure (ELF)	MIL-STD-883, Method 1015	1x300	Pass
		3x100	Pass
		1x500	Pass
		3x170	Pass
		2x505	Pass
		1x101	Pass
		1x310	Pass
		2x350	Pass
		4x505	Pass
		2x400	Pass
		1x110	Pass
		1x100	Pass
		2x480	Pass
		1x50	Pass
		1x350	Pass
1x300	Pass		
Highly Accelerated Stress Test (HAST)*	JEDEC-STD-22-Method A110	3x45	Pass
		3x20	Pass
		1x45	Pass
		1x25	Pass
High Temperature Storage (HTS)	JEDEC-STD-22-Method A103	3x45	Pass
		3x45	Pass
		4x45	Pass
		1x55	Pass
High Temperature Operating Life (HTOL)	JEDEC-STD-22-Method A108	3x45	Pass
		1x45	Pass
		3x45	Pass
		4x45	Pass
		1x77	Pass
		1x45	Pass
		1x45	Pass
		1x77	Pass
		6x77	Pass
		4x50	Pass
3x50	Pass		